



IECQ QUALITY ASSESSMENT SYSTEM (IECQ)

For rules and details of the IECQ visit www.iecq.org

IECQ Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.:	IECQ-L DEKRA 16.0002	Issue No.:	6	Status:	Draft
Supersedes:	IECQ-L DEKRA 16.0002 Issue 5	Issue Date:	2025/07/20	Org Issue:	2016/08/17
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Integrated Service Technology, Inc.

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The organization, facilities and procedures have been assessed by the IECQ Certification Body in accordance with IECQ 03-1 and IECQ 03-6 for issuance of this certificate and found to be in conformity with the applicable requirements of the IECQ Independent Testing Laboratory Assessment Program Requirements Scheme and in respect of ISO/IEC 17025:2017 for the testing of component product under the IECQ.

Scope:

Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

See attached Schedule of Scope

-- Attached Schedule: IECQ-L DEKRA 16.0002-S.pdf --

Approved by Certification Body (CB): DEKRA Certification B.V.

Meander 1051
Arnhem
Netherlands

Authorized person:
Ted Gaertner



The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.

This Certificate of Conformity may be suspended or withdrawn in accordance with the Rules of Procedure of the IECQ System and its Schemes.

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Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L DEKRA 16.0002

CB Certificate No.: DEKRA-T5A-003

Schedule Number: IECQ-L DEKRA 16.0002-S

Rev No.: 6

Revision Date: 2025/07/20

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Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

Description test	Standard
Steady-Status Temperature and Humidity Bias Life Test (THB)	JESD22-A101, AEC-Q100, AEC-Q101, AEC-Q200, MIL-STD-202
High Humidity High Temp. Reverse Bias (H3TRB)	JESD22-A101, AEC-Q101
Power and Temperature Cycling (PTC)	JESD22-A105, AEC-Q100, AEC-Q101
High Temperature Operation test (HTOL)	JESD22-A108, AEC-Q100, AEC-Q200, MIL-STD-202
Low Temperature Operation test (LTOL)	JESD22-A108
High Temperature Reverse Bias (HTRB)	JESD22-A108, AEC-Q101, MIL-STD-750, MIL-STD-883
High Temperature Gate Bias (HTGB)	JESD22-A108, AEC-Q101
Early Life Failure Rate (ELFR)	JESD22-A108, AEC-Q100
Highly Accelerated Stress Test (HAST)	JESD22-A110, AEC-Q100, AEC-Q101
Electrically Erasable Programmable ROM (EEPROM) Program/Erase Endurance and Data Retention Stress Test (Endurance and Data Retention)	JESD22-A117, AEC-Q100,
Power Cycling	JESD22-A122
NVM Endurance, Data Retention, and Operation Life (EDR)	AEC-Q100
Electromigration (EM)	JEP001, JESD61, JESD87, AEC-Q100
Stress Migration (SM)	JEP001, JEP139, JESD87, AEC-Q100
Steady-Status operation life	MIL-STD-750, MIL-STD-883
SAT	J-STD-020
2D X-ray	IPC-A-610
3D X-ray	A00-340-30071
3D OM	A00-340-30066
Reflow test	J-STD-020

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DEKRA Certification B.V. Meander 1051, Arnhem. Netherlands





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Solderability test		J-STD-020, JESD22-B102
Chemical Analysis		IEC62321, EN14582, IPC-TM-650
X-section/ SEM		IPC-TM-650, IPC-A-610, JESD22-A121A
OBIRCH		A00-510-30003
InGaAs		A00-510-30028
Thermal EMMI		A00-510-30038
Surge		A00-510-30043
TLP		A00-510-30010
I-V measurement		A00-510-30029
Sample Preparation (Decap)		A00-520-30041
2nd level integration platform service (Military)	Pre-SMT	J-STD-020, JESD22-A113
	SMT	IPC-7525, IPC-A-610, JESD22-A111, J-STD-002, J-STD-003, MIL-STD-202
	Temperature Cycling test	IPC-9701, JESD22-A104, JESD22-A106 EIAJ ED-4702, AEC-Q007, AEC-Q104 IEC-60068-2-14, MIL-STD-202, MIL-STD-750, MIL-STD-810, MIL-STD-883
	Temperature-Humidity test	JESD22-A101, MIL-STD-202, MIL-STD-750, MIL-STD-810, MIL-STD-883
	Drop/Shock	JESD22-B110, JESD22-B111, AEC-Q104 MIL-STD-202, MIL-STD-750, MIL-STD-810, MIL-STD-883
	Vibration	JESD22-B103, AEC-Q104, MIL-STD-202 MIL-STD-750, MIL-STD-810, MIL-STD-883
	Hermeticity	JESD22-A109
	Package Warpage Measurement of Surface-Mount Integrated Circuits at Elevated Temperature	JESD22-B108, JESD22-B112, JESD22-B110
	Printed Wiring Board Strain Gage Test	IPC-9703

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